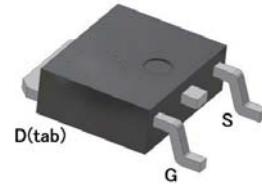
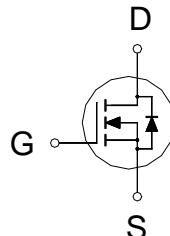


**N-Channel Logic Level Enhancement Mode Field Effect Transistor**
**Product Summary:**

$BV_{DSS}$	60V
$R_{DS(on)}$ (MAX.)	$20\text{m}\Omega$
$I_D$	25A

UIS,  $R_g$  100% Tested

Pb-Free Lead Plating &amp; Halogen Free


**ABSOLUTE MAXIMUM RATINGS ( $T_c = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_c = 25^\circ\text{C}$	$I_D$	25	A
	$T_c = 100^\circ\text{C}$		16	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	100	
Avalanche Current		$I_{AS}$	20	
Avalanche Energy	$L = 0.1\text{mH}, I_D=20\text{A}, R_G=25\Omega$	$E_{AS}$	20	mJ
Repetitive Avalanche Energy <sup>2</sup>	$L = 0.05\text{mH}$	$E_{AR}$	10	
Power Dissipation	$T_c = 25^\circ\text{C}$	$P_D$	50	W
	$T_c = 100^\circ\text{C}$		20	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$	2.5	2.5	°C / W
Junction-to-Ambient	$R_{\theta JA}$		75	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle ≤ 1%

**ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)**

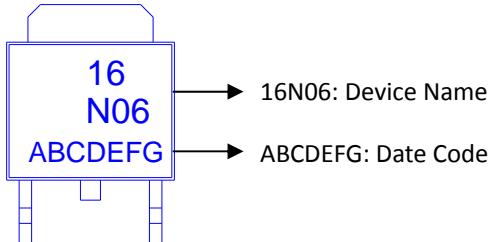
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.2	1.8	3.2	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48V, V_{GS} = 0V$			1	$\mu\text{A}$
		$V_{DS} = 40V, V_{GS} = 0V, T_J = 125^\circ\text{C}$			25	
On-State Drain Current <sup>1</sup>	$I_{D(\text{ON})}$	$V_{DS} = 5V, V_{GS} = 10V$	25			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 10V, I_D = 20A$		16	20	$\text{m}\Omega$
		$V_{GS} = 7V, I_D = 15A$		19	24	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 5V, I_D = 20A$		25		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1\text{MHz}$		2240		$\text{pF}$
Output Capacitance	$C_{oss}$			172		
Reverse Transfer Capacitance	$C_{rss}$			145		
Gate Resistance	$R_g$	$V_{GS} = 15\text{mV}, V_{DS} = 0V, f = 1\text{MHz}$		2.0		$\Omega$
Total Gate Charge <sup>1,2</sup>	$Q_g$	$V_{DS} = 30V, V_{GS} = 10V, I_D = 20A$		43		$\text{nC}$
Gate-Source Charge <sup>1,2</sup>	$Q_{gs}$			7.2		
Gate-Drain Charge <sup>1,2</sup>	$Q_{gd}$			11		
Turn-On Delay Time <sup>1,2</sup>	$t_{d(\text{on})}$	$V_{DS} = 30V, I_D = 1A, V_{GS} = 10V, R_{GS} = 6\Omega$		20		$\text{nS}$
Rise Time <sup>1,2</sup>	$t_r$			12		
Turn-Off Delay Time <sup>1,2</sup>	$t_{d(\text{off})}$			50		
Fall Time <sup>1,2</sup>	$t_f$			25		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				25	$\text{A}$
Pulsed Current <sup>3</sup>	$I_{SM}$				100	
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	$t_{rr}$	$I_F = 25A, dI_F/dt = 100A / \mu\text{s}$		60		$\text{nS}$
Reverse Recovery Charge	$Q_{rr}$			42		

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

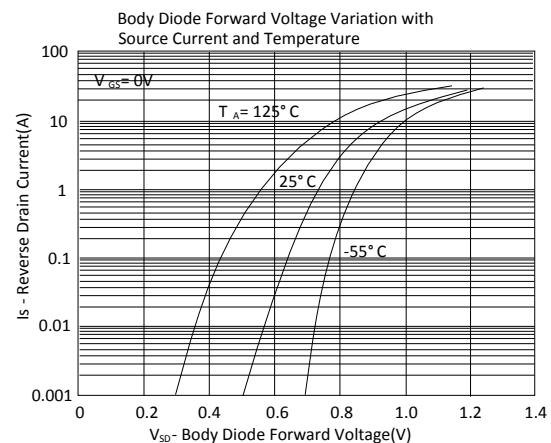
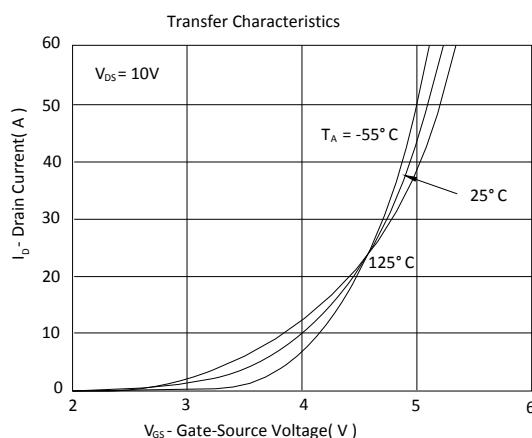
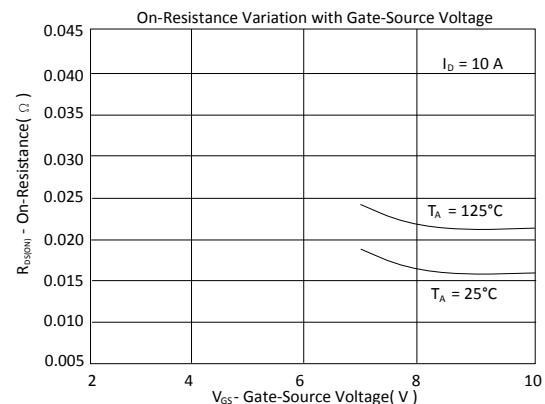
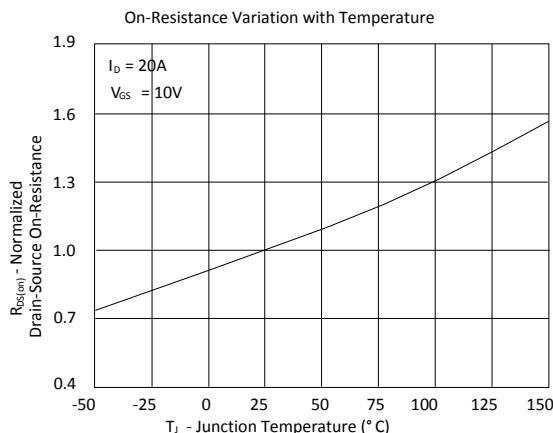
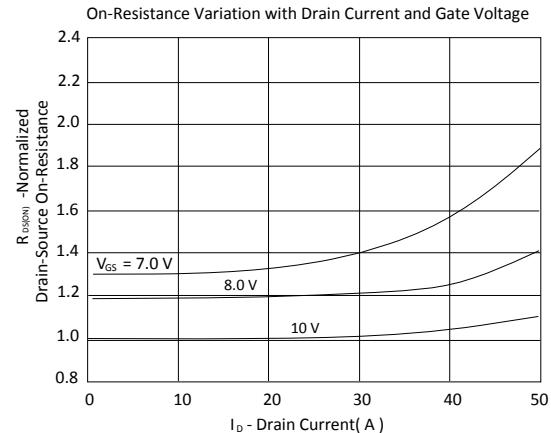
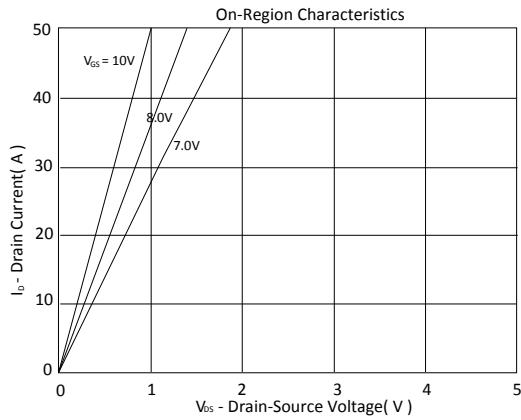
<sup>3</sup>Pulse width limited by maximum junction temperature.

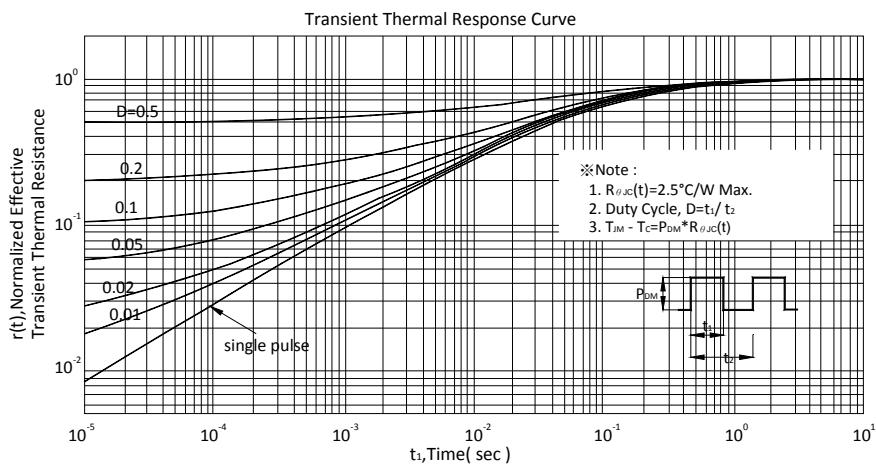
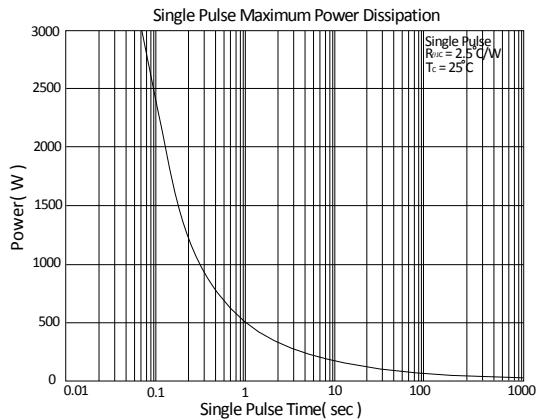
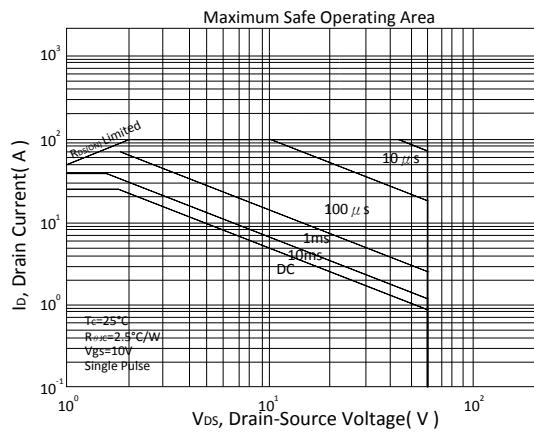
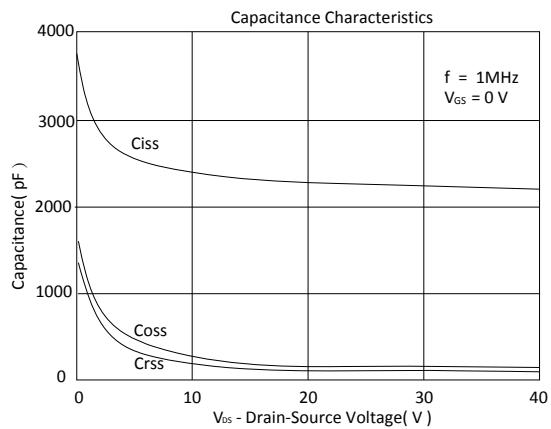
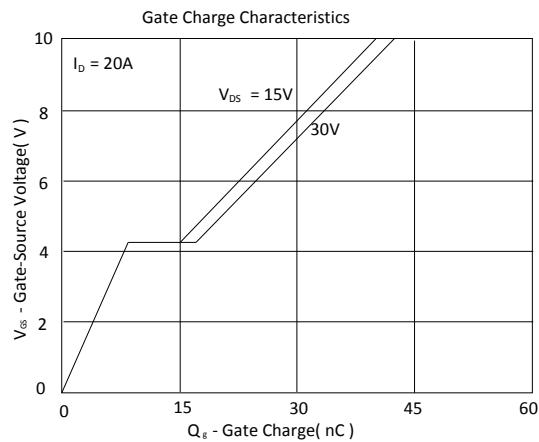
**Ordering & Marking Information:**

Device Name: LB16N06D for DPAK (TO-252)

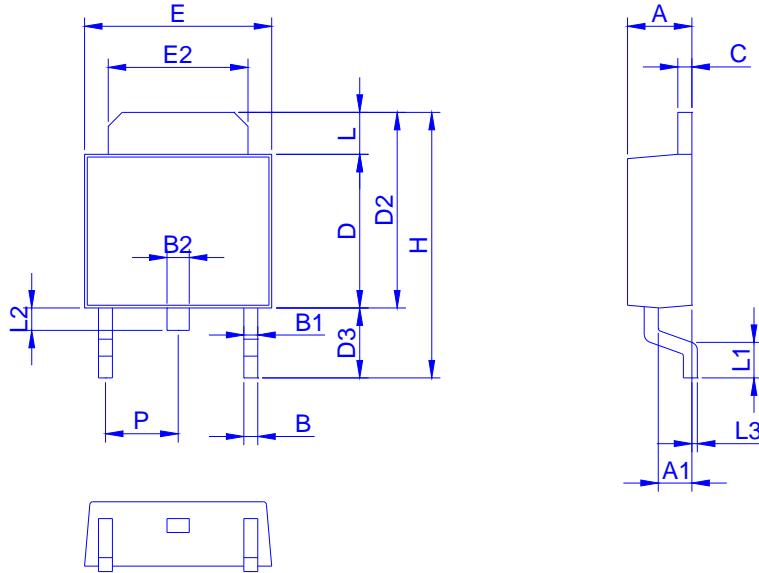


### TYPICAL CHARACTERISTICS





### Outline Drawing



Dimension in mm

Dimension	A	A1	B	B1	B2	C	D	D2	D3	E	E2	H	L	L1	L2	L3	P
Min.	2.10	0.95	0.30	0.40	0.60	0.40	5.30	6.70	2.20	6.40	4.80	9.20	0.89	0.90	0.50	0.00	2.10
Max.	2.50	1.30	0.85	0.94	1.00	0.60	6.20	7.30	3.00	6.70	5.45	10.15	1.70	1.65	1.10	0.30	2.50

### Footprint

